Software Development for µSR Experiment at J-PARC

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J-PARC MLF S-Line

J-PARC MLF MUSE

 High intensity pulsed muon beam

High-rate capable Spectrometer

- ARTEMIS & CYCLOPS
- Segmented scintillation detector with SiPM

	Max B	Detector	Channel
ARTEMIS	0.4 T	10 mm sq. Sci. telescope	1,280 ch
CYCLOPS	5 T	1 mm sq. x45 mm Fiber sci.	3,008 ch





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Standard µSR

Sample environment must be stable

- Time required to change sample environment ≒ µSR data acquisition
- The measurement must be stopped during the change



Transient µSR

New µSR measurement actively changing the environment during the measurement

 Matching the µSR result and environment information at every pulse

> Environment Information

High intensity pulse muon beam is useful

Conventional

μSR

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Transient

μSR

Development of Transient µSR

Analysis tool

- Integration of µSR data and sample environment data
- Creating histogram
- It works by just installing ROOT with default option
- Anyone can use it
- Even if you do not know how to use ROOT
- You can analyze the data with just a click of a button



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Transient µSR Measurement

First Transient µSR experiment @ S-Line

Target Material | MnSi (Changing temperature)



MnSi Transient µSR

MnSi ZF

- Kubo-Toyabe was observed
- Reasonable Tk
 (~30 K)

Difficult to analyze in 3D

Analyzing tool to create 2D Hist. were developed



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Demonstration of Analysis Tools for Transient µSR

High temperature resolution



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LCR Measurement

Changing LF during the Run

Fast scan (2sec/point, 13 min/1scan)



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Summary

Transient µSR

- Changing temperature or magnetic field during measurement
- We can save the time by measuring during heating and cooling
- Precision measurement of transition point
- New analysis tools
- Based on ROOT